

<b>Notice of References Cited</b>	Application/Control No. 10/560,189		Applicant(s)/Patent Under Reexamination YOSHIDA, AKIRA	
	Examiner HENRY S. HU		Art Unit 1796	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,391,460 B1	05-2002	Tanaka et al.	428/421
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO-2004/108819 A1	12-2004	WO	Yoshida, Akira	-----
*	O	JP-2000-052369	02-2000	JP	Akira et al.	-----
*	P	JP-04-268357	09-1992	JP	Fumio et al.	-----
*	Q	JP-07-053821	02-1995	JP	Nobuo et al.	-----
*	R	JP-07-026052	01-1995	JP	Yasuhiro et al.	-----
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
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	X				

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